EER O L MAN STEELER

January 28, 2004

To: Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Fr: George O. Saile, Reg. No. 19,572 28 Davis Avenue Poughkeepsie, N.Y. 12603

Subject:

Serial No. 10/725,852 12/02/03

Yi-Hsun Wu et al.

AN EFFECTIVE VCC TO Vss POWER ESD PROTECTION DEVICE

## INFORMATION DISCLOSURE STATEMENT

Enclosed is Form PTO-1449, Information Disclosure Citation
In An Application.

The following Patents and/or Publications are submitted to comply with the duty of disclosure under CFR 1.97-1.99 and 37 CFR 1.56.

## CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Commissioner for Patents P.O. Box 1450, Alexandria, Va 22313-1450 on February  $\lambda$ , 2004.

Stephen B. Ackerman, Reg.# 37761

Signature/Date 2204

TSMC-01-088B

U.S. Patent 5,898,205 to Lee, "Enhanced ESD Protection Circuitry," describes an ESD protection circuit using NMOS and PMOS devices.

U.S. Patent 5,953,601 to Shiue et al., "ESD Implantation Scheme for 0.35uM 3.3V 70A Gate Oxide Process," discloses an ESD implantation step using boron.

U.S. Patent 5,929,493 to Wu, "CMOS Transistors with Self-Aligned Planarization Twin-Well by Using Fewer Mask Counts," teaches a CMOS process using blanket, low dose boron implant to adjust Vth for ESD protection devices.

U.S. Patent 5,559,352 to Hsue et al., "ESD Protection Improvement," discloses a method to improve an ESD protection device using ion implantation.

Sincerely,

Stephen B. Ackerman,

Reg. No. 37761

Form PTO-1449 Doctor Humber (Openne) Application H OF ENEORMATION DISCLOSURE CITATION IN AN APPLICATION Fling Date (Usio soveral shoots il necessary) U. S'. PATENT DOCUMENTS EXAMINE BY DOCUMENT NUMBER TUMO DATE

Y APPROPRIATE DATE KULE CLUE BUSCLES 355 257 438 200 257 369 Hsue et 328 257 FOREIGN PATENT DOCUMENTS Translation DOCUMENT NUMBER DATE COUNTRY cuss SUBCLASS YES NO OTHER DOCUMENTS (Including Luthor, Title, Date, Pertinent Pages, Etc.)

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.

DATE CONMIDERED

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